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		REPRESENTATIVE DIVISION RF DEVICES DIV.

DEVICE SPECIFICATION for
DIGITAL DBS TUNER with LINK

MODEL NO. BS2F7HZ0169

☐ CUSTOMER'S APPROVAL

DATE

BY

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[1] GENERAL SPECIFICATIONS

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SHARP**[2] MECHANICAL SPECIFICATION**

- 2-1. Dimension and mounting details see section [14]
- 2-2. Mass 40.56g
- 2-3. Strength of F-connector No severe transform or distortion at bending moment, 0.98N·m. To be connected electrically.
- 2-4. Clamp Torque of F-connector No severe transform or distortion on the connection with F-connector at bending moment, 0.98N·m. To be connected electrically.

**[3] ENVIRONMENTAL SPECIFICATION
(ELECTRICAL FUNCTIONAL OPERATION GUARANTEE)**

- 3-1. Operating Temperature 0deg.C to +60deg.C
Humidity Less than 85%
No condensation
- 3-2. Storage Temperature -20deg.C to +85deg.C
Humidity Less than 95%
Water vapor pressure 6643Pa max, without condensation

<Notice>

Please be careful that sudden temperature changes may cause condensation during storage, and such condensation may cause corrosion.

[4] ABSOLUTE MAXIMUM VOLTAGE

Table 1;

Pin name	Pin No.	MIN.	MAX	UNIT	Note
B1B	1		25	V	400mA max.
B1A	2		25	V	400mA max.
B4	3	-0.3	3.63	V	
B2	4	-0.3	3.6	V	
B3	11	-0.25	3.63	V	
VDD	13	-0.1	1.26	V	
I/O pins	8, 9, ...	-0.3	B3+0.3	V	

[5] TESTING CONDITION**5-1. Supply voltage**

Table 2;

Pin name	Pin No.	MIN.	TYP.	MAX.	UNIT	Note
B4	3	3.25	3.30	3.35	V	
B2	4	3.25	3.30	3.35	V	
B3	11	3.25	3.30	3.35	V	
VDD	13	1.03	1.05	1.07	V	

5-2. Ambient temperature 25deg.C +/- 5deg.C

5-3. Ambient humidity 65% +/- 10%

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[6] ELECTRICAL CHARACTERISTIC (Unless otherwise stated testing condition 5-1~5-3.)
Table3;

No.	Item		Specification				Condition
			MIN.	TYP.	MAX.	UNIT	
6-1	RF input VSWR			2.0	2.5		950MHz to 2150MHz
6-2	Noise figure(at max. gain)			6	12	dB	V _{agc} =0.3V
6-3	2tone IM3 UD1=F _o +29.5MHz, UD2=F _o +59.0MHz			-55	-40	dBc	RFIN=-25dBm BBOU=250mVp-p BB_GAIN=0x8(16dB)
6-4	Maximum conversion gain			80		dB	AGC=3.0V, BB_GAIN=0x8(16dB)
6-5	Minimum conversion gain			-10		dB	AGC=0.3V, BB_GAIN=0x8(16dB)
6-6	AGC range			90			
6-7	PLL settling time			50	200	us	limited to STV6110A
6-8	PLL phase noise	1kHz offset		-81		dBc/H z	I _{cp} =500uA
		10kHz offset		-87			
		100kHz offset		-90			
6-9	L.O. leak at RF input terminal				-70	dBm	950MHz to 2150MHz
6-10	Current consumption	B2		220	260	mA	
		B3		100	120	mA	
		B4		25	40	mA	
		VDD(average)		500	600	mA	Using ST software
		VDD(peak)			1800	mA	The regulator should be dimensioned to provide this maximum value
6-11	RF output VSWR			2.0	2.5		
6-12	RF output gain		-5	0	+5	dB	

[7] ERROR RATE PERFORMANCE

Table 4-1; Es/No performance at Quasi Error Free (DVB-S2 mode)

Mode	ETSI Ideal	Performance (Typical)	Unit	Note
QPSK 1/2	1.00	1.2	dB	>DVB-S2 >Pilot: ON >BW = Symbol_rate >BERTester: SFU
QPSK 3/5	2.23	2.4		
QPSK 2/3	3.10	3.2		
QPSK 3/4	4.03	4.2		
QPSK 4/5	4.68	4.8		
QPSK 5/6	5.18	5.3		
QPSK 8/9	6.20	6.4		
QPSK 9/10	6.42	6.6		
8PSK 3/5	5.50	5.8		
8PSK 2/3	6.62	6.8		
8PSK 3/4	7.91	8.1		
8PSK 5/6	9.35	9.6		
8PSK 8/9	10.69	10.9		
8PSK 9/10	10.98	11.3		

Table 4-2; E_b/N₀ performance at Quasi Error Free (DVB-S mode)

Code rate	DVB-S standard (Maximum)	Performance (Typical)	Unit	Note
QPSK 1/2	4.5	3.7	dB	>DVB-S >post Vitebi BER=2x10 ⁻⁴
QPSK 2/3	5.0	4.2		
QPSK 3/4	5.5	4.7		
QPSK 5/6	6.0	5.3		

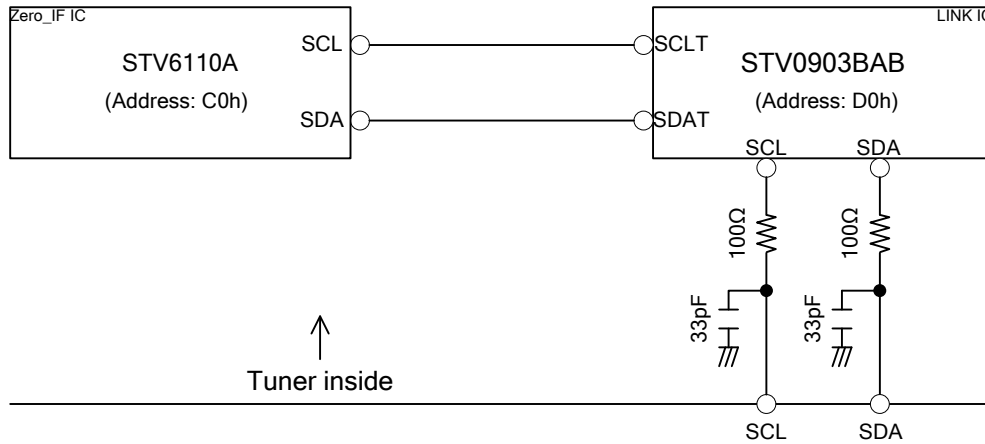
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QPSK 7/8	6.4	5.7		
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SHARP**[8] I²C INTERFACE SPECIFICATION****8-1. Internal connection**

The Internal I²C connection diagram of this tuner is as following figure. It is using the I²C private repeater of STV0903BAB for tuner isolation.

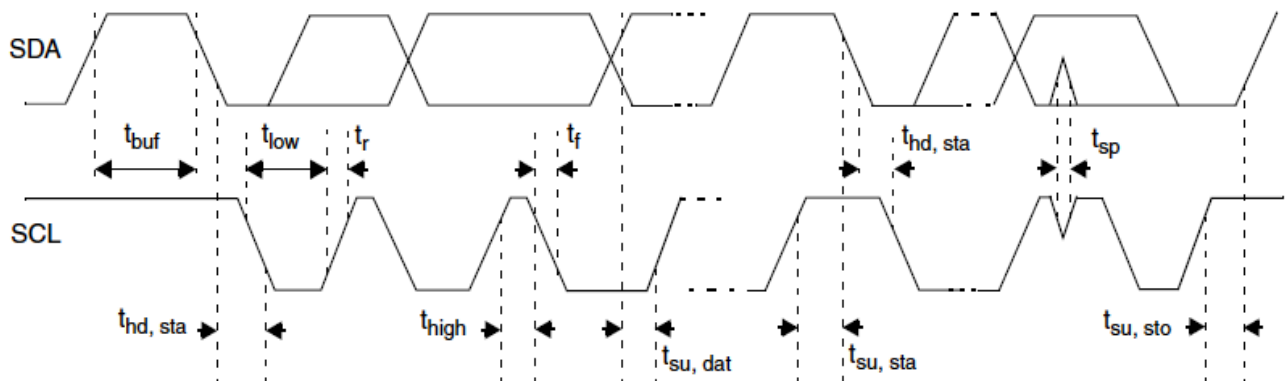


note) The STV0903 main I²C bus can work up to 400kHz, but the I²C repeater bus should be limited to 250kHz(ENARPT level 4)

8-2. Main I2C bus characteristic (conforms to the specification of STV0903BAB)

Table 5;

Item	Symbol	MIN.	MAX.	Unit	Note
Input high voltage	V_{ih}	2.0	3.6	V	
Input low voltage	V_{il}	-0.5	0.8	V	
SCL clock rate	f_{scl}		400	kHz	Fast mode
Bus free time between a stop and start condition	t_{buf}	1.3		us	
Hold time (repeated) start condition	$t_{hd, sta}$	0.6		us	After this period, the first clock pulse is generated.
Low period of the SCL	t_{low}	1.3		us	
High period of the SCL	t_{high}	0.6		us	
Rise time for SDA and SCL	t_r		300	ns	Fast mode
Fall time for SDA and SCL	t_f		300	ns	Fast mode
Setup time for a repeated start condition	$t_{su, sta}$	0.6		us	
Setup time for stop condition	$t_{su, sto}$	0.6		us	
Data setup time	$t_{su, dat}$	100		ns	
Pulse width of spikes to be suppressed by input filter	t_{sp}		50	ns	Fast mode

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[9] STV6110A PROGRAMMING

9-1. Tuning overview

When the PLL is locked, the frequency of the local oscillator is given by:

$$f_{LO} = N * f_{XTAL} / R / P = f_{VCO} / P = f_{LOstep} * N$$

f_{VCO} : The frequency of VCO output, set up using registers [TUNING1](#) and [TUNING2](#).

f_{XTAL} : The frequency of crystal oscillator output

N: The division ratio of the N-integer divider, programmed in bitfield N_DIV

R: The division ratio R of the reference divider, controlled through R_DIV[1:0]

P: The division ratio P of the post divider, controlled using bit DIV4SEL.

The VCO operates from $f_{VCO} = 2600$ MHz to 5200 MHz. In order to generate a LO frequency (f_{LO}) from 950 MHz to 2150 MHz, the appropriate value of P has to be selected (2 or 4).

For input frequencies below 1300 MHz the P divider has to be set to 4.

For input frequencies above 1300 MHz, the P divider has to be set to 2.

To keep the step constant between all the LO frequencies (f_{LOstep}), the product of R and P must be kept constant.

For example, if $f_{XTAL} = 16$ MHz, $f_{LO} = 2150$ MHz and $f_{LOstep} = 1$ MHz then the VCO frequency could be either 4300 MHz ($2 * f_{VCO}$) or 8600 MHz ($4 * f_{VCO}$). However, f_{VCO} must lie within the range 2600 MHz to 5200 MHz, hence $P = 2$.

Also, $N = f_{LO} / f_{LOstep} = 2150$.

The last unknown, $R = f_{XTAL} / (P * f_{LOstep}) = 8$.

[Table 6](#) shows the values for bits 4 and 5 of register [TUNING2](#) for different RF input frequencies.

Table 6; Frequency ranges and divider register settings

RF_IN frequency (MHz)	LO divisor, P	VCO frequency	DIV4SEL	PRESC32ON
950 - 1024	4	3800 - 4092	1	0
1024 - 1300	4	3968 - 5200	1	1
1300 - 2048	2	2600 - 4092	0	0
2048 - 2150	2	3968 - 4300	0	1

After N is modified the VCO calibration must be carried out.

9-2. Calibration setting

The reference clock used by the calibration functions is 1 MHz. It is generated from the crystal oscillator by a divider which is set up in bitfield K[4:0] in register [CTRL1](#).

The bandwidth calibration requires that:

$$f_{XTAL} / (K + 16) = 1 \text{ MHz}$$

If the crystal frequency is fixed by the application to 16 MHz, then, K has to be set to 0.

This reference clock is used by all the calibration functions.

<<VCO calibration>>

The VCO must be calibrated after N_DIV is reprogrammed. The calibration is started by setting bit CALVCO_STRT = 1 in register [STAT1](#). It runs automatically. After the settling time of the synthesizer, the chip writes 0 into CALVCO_STRT to indicate that the calibration is completed.

<<LPF calibration>>

The low-pass filter cut-off frequency must be calibrated after CF[4:0] is reprogrammed. The calibration is started by setting bit CALRC_STRT = 1 in register [STAT1](#) and it runs automatically. To indicate the calibration is completed, the chip writes 0 into the CALRC_STRT.

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9-3. Registers

The registers are automatically reset to their default values at power up by a power-on-reset (POR).

Table 7;

Name	Addr	Reset	Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0	
CTRL 1	0x0	0x5F	K[4:0]						LPT	RX	SYN
CTRL 2	0x1	0x33	CO_DIV[1:0]		1	REFOU TSEL	BB_GAIN[3:0]				
TUNI NG0	0x2	0x30	N_DIV[7:0]								
TUNI NG1	0x3	0xC7	R_DIV[1:0]		PRESC 32ON	DIV4 SEL	N_DIV[11:8]				
CTRL 3	0x4	0x12	DCLOP OFF	0	ICP	CF[4:0]					
STAT 1	0x5	0x06	Reserved for test: set to 0						CALVCO _STRT	CALRC _STRT	LOCK
STAT 2	0x6	0x00	Reserved for test: set to 0								
STAT 3	0x7	0x00	Reserved for test: set to 0								

K[4:0]: determines the divider value for setting the calibration frequency (see [Section 9-2.](#)).
The application requires a calibration frequency of 1 MHz.

LPT, RX, SYN: These three bits set the operating level. Only four combinations are allowed as given in the table below:

LPT	RX	SYN	Operating levels		
			Loop-through	Synthesizer (VCO, PFD, CP, Dividers)	LNA, Mixer, LPF, PGA and Buffers
0	0	0	Off	Off	Off
1	1	1	On	On	On
0	1	1	Off	On	On
1	0	0	On	Off	Off, except the LNA
All other combinations			Reserved: not to be used		

CO_DIV[1:0]: sets the crystal oscillator divisor value, CO, for the output clock:
00: divide by 1 (output frequency is f_{XTAL}) (default)
01: divide by 2
10: divide by 4
11: divide by 8

REFOUTSEL: sets the DC voltage on pins IP, IN, QP, QN:
0: VCC / 2
1: 1.25 V (default)

BB_GAIN[3:0]: sets the baseband amplifier gain. When the amplifier is on, the gain is increased as follows:

0x0: 0 dB
0x1: 2 dB
0x2: 4 dB
0x3: 6 dB (default)
0x4: 8 dB
0x5: 10 dB
0x6: 12 dB
0x7: 14 dB
0x8: 16 dB (recommend)
0x9-0xF: not used.

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N_DIV[7:0]: the LSBs of N_DIV[11:0], which sets the N-integer divider value, N.

N_DIV[11:8]: the MSBs of N_DIV[11:0], which sets the N-integer divider value N.

R_DIV[1:0]: sets the divisor, R, for the reference divider:

- 00: 2
- 01: 4
- 10: 8
- 11: 16 (default)

PRESC32ON: selects the divisor for the pre-scaler divider:

- 0: 16 (default)
- 1: 32

DIV4SEL: selects the divisor, P, for the post divider:

- 0: 2 (default)
- 1: 4

DCLOOP_OFF: selects the DC offset compensation loop:

- 0: compensation disabled (default)
- 1: compensation enabled

ICP: sets the value of the charge pump current:

- 0: 500 μ A (default)
- 1: 1.0 mA

CF[4:0]: sets the baseband filter cut-off frequency:

- | | |
|------------------------|--------------|
| 0x00: 5 MHz | 0x01: 6 MHz |
| 0x02: 7 MHz | 0x03: 8 MHz |
| 0x04: 9 MHz | 0x05: 10 MHz |
| 0x06: 11 MHz | 0x07: 12 MHz |
| 0x08: 13 MHz | 0x09: 14 MHz |
| 0x0A: 15 MHz | 0x0B: 16 MHz |
| 0x0C: 17 MHz | 0x0D: 18 MHz |
| 0x0E: 19 MHz | 0x0F: 20 MHz |
| 0x10: 21 MHz | 0x11: 22 MHz |
| 0x12: 23 MHz (default) | 0x13: 24 MHz |
| 0x14: 25 MHz | 0x15: 26 MHz |
| 0x16: 27 MHz | 0x17: 28 MHz |
| 0x18: 29 MHz | 0x19: 30 MHz |
| 0x1A: 31 MHz | 0x1B: 32MHz |
| 0x1C: 33 MHz | 0x1D: 34 MHz |
| 0x1E: 35 MHz | 0x1F: 36 MHz |

CALVCO_STRT: automatic calibration of VCO:

- 0: VCO calibration finished
- 1: start VCO calibration (default)

CALRC_STRT: automatic calibration of the low-pass filter:

- 0: filter calibration finished
- 1: start filter calibration (default)

LOCK: indicates when loop is locked:

- 0: not in lock
- 1: locked

SHARP**[10] Reliability****10-1. High temperature high humidity load (40deg.C, 90% RH, 500h)**

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial value.
- 2) After cycling DUT in the constant chamber at 40deg.C/90-95% RH in on state, for total 500h, leave the DUT at room temperature and humidity for 2h and then measure value after test.
- 3) Must meet the specifications of Table 17.

10-2. High temperature load (70deg.C, 40% RH, 500h)

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial value.
- 2) After leaving DUT in the constant chamber at 70+/-2deg.C/40% RH for total 500h, leave the DUT at room temperature and humidity for 2h and then measure value after test.
- 3) Must meet the specifications of Table 17.

10-3. Cold test (-25deg.C, 500h)

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial value.
- 2) After leaving DUT in the constant temperature chamber at -25deg.C for 500h, leave the DUT at room temperature and humidity for 2h and then measure the values after test.
- 3) Must meet the specifications of Table 17.

10-4. Shock (686 m/s², 6 planes, 3 times)

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial values.
- 2) Using the shock tester, apply shock of 686 m/s² three times to each of 6 planes and then measure the values.
- 3) Must meet the specifications of Table 17.
- 4) This test is to be conducted using a single tuner.

10-5. Vibration (10-55 Hz, 1.5 mm, in each of three mutually perpendicular directions, each 2 times)

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial values.
- 2) Using the vibration tester, apply motion having an amplitude of 1.5 mm (constant), the frequency being varied uniformly between 10 and 55 Hz, to DUT, for 2h in each of three mutually perpendicular directions (X, Y and Z, total of 6h). After the test, measure the values.
- 3) Must meet the specifications of Table 17.
- 4) This test is to be conducted using a single tuner.

10-6. Heat shock test (1 cycle=1h (-20deg.C; 0.5h, 70deg.C;0.5h), 50 cycles))

- 1) After leaving DUT at room temperature and humidity for 24h or longer, measure the initial value.
- 2) Using the heat shock tester, apply heat shock to DUT. After the test, measure the values.
- 3) Must meet the specifications of Table 17.

10-7. Solderability of terminal

Pretreatment of heating terminal at 150deg.C for 1h is performed and leave it at room temperature for 2h or longer. Immerse 1.9 mm length of terminal (from the tip) to be soldered into rosin (JIS-K-5902), isopropyl alcohol (JIS-K-8839 or JIS-K-1522, rosin concentration (10-35% range) approx. 25% by weight unless otherwise specified) or equivalent solution for 3-5s, and then immerse the length of the terminal into a pool of molten solder (Sn/3.0Ag/0.5Cu, or equivalent) at 240 +/-2deg.C for 3s. Dipped terminal portion shall be wetted by more than 95%. (Excluding the cutting plane of the chassis)

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10-8. Soldering heat resistance

Immerse the terminal mounted on a PCB (1.6t thick) into solder at 350±5deg.C for 3.0-3.5 seconds or at 260 +/-5deg.C for 10 +/-1 seconds. Remove the PCB from the solder and leave it for 1 hour at room temperature. The test sample shall show no degradation in appearance and electrical characteristics.

10-9. ESD protection

Table 16; ESD Test Condition (IEC61000-4-2 Compliant)

Terminal	Limits	Condition
RF_IN (coaxial center)	+/-6kV DC	150pF/330ohm (The varistor is connected between LNB terminal and GND.) each 5 times
Others	+/-200V DC	150pF/330ohm each 5 times

10-10. Judgment

Table 17; Specifcation after the reliability tests

Item		Spec.	UNIT	Condition
Current consumption	B2	< 300	mA	3.3V
	B3	< 120	mA	3.3V
	B4	< 40	mA	3.3V
	VDD	< 600	mA	1.05V
Es/No at QEF	8PSK 3/4	< 8.2	dB	DVB-S2, Pilot: ON

Note) All TS outputs are checked with SFU. Other I/O pins are checked with oscilloscope.

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[11] BLOCK DIAGRAM

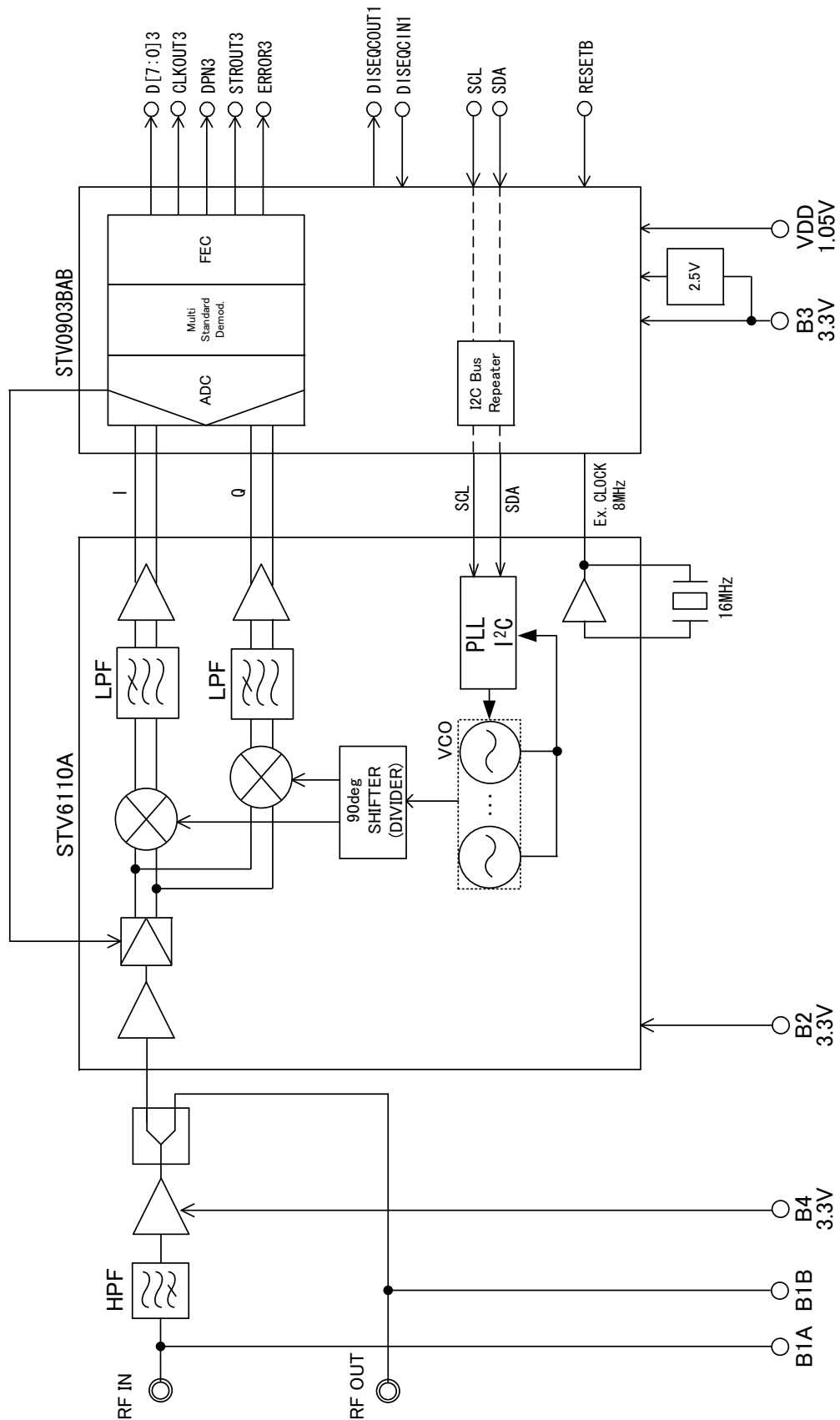


Fig 1. BLOCK DIAGRAM

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[12] PIN LIST

No.	NAME	LOGIC	PIN DESCRIPTION
1	B1B		Voltage supply of LNB B. Please ground it with a 1000pF ceramic capacitor.
2	B1A		Voltage supply of LNB A. Please ground it with a 1000pF ceramic capacitor.
3	B4		3.3V supply for RF booster amp.
4	B2		3.3V supply for STV6110. Please keep a ripple at the Power Supply less than 10mVp-p.
5,6,7	NC		It is not connected inside the unit.
8	SDA	3.3V	I ² C Bus. Please connect a pull-up resistor which is more than 2k ohm outside of the tuner.
9	SCL	3.3V	
10	DISEQCIN1	3.3V	DiSEqC 1 input
11	B3		3.3V supply for STV0903. It is internally converted into 2.5V.
12	DISEQCOUT 1	3.3V	DiSEqC 1 output.
13	VDD		1.0V supply for STV0903.
14,...,21	D03,...,D73	3.3V	Transport stream 3 data.
22	CLK_OUT	3.3V	Transport stream 3 clock out.
23	D/PN	3.3V	Transport stream 3 data parity.
24	STROUT	3.3V	Transport stream 3 sync.
25	ERROR	3.3V	Transport stream error.
26	RESETB	3.3V	Chip reset active low.

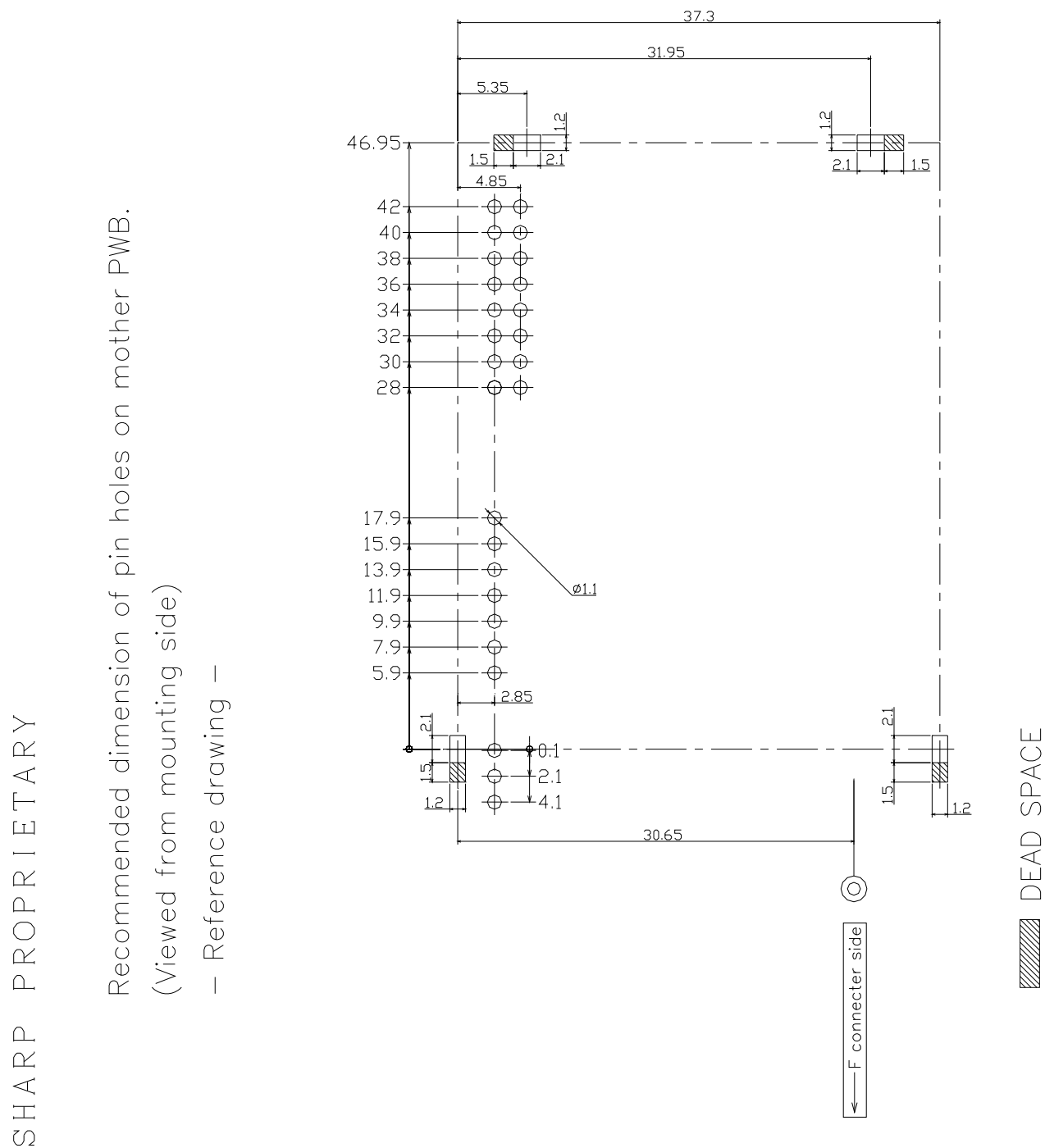
Note: The 3.3 V digital I/Os comply to the JEDEC standard JESD8b..

Note: Pin RESETB, the chip reset, must remain active (low) until at least 3 ms after the last power supply has stabilized.

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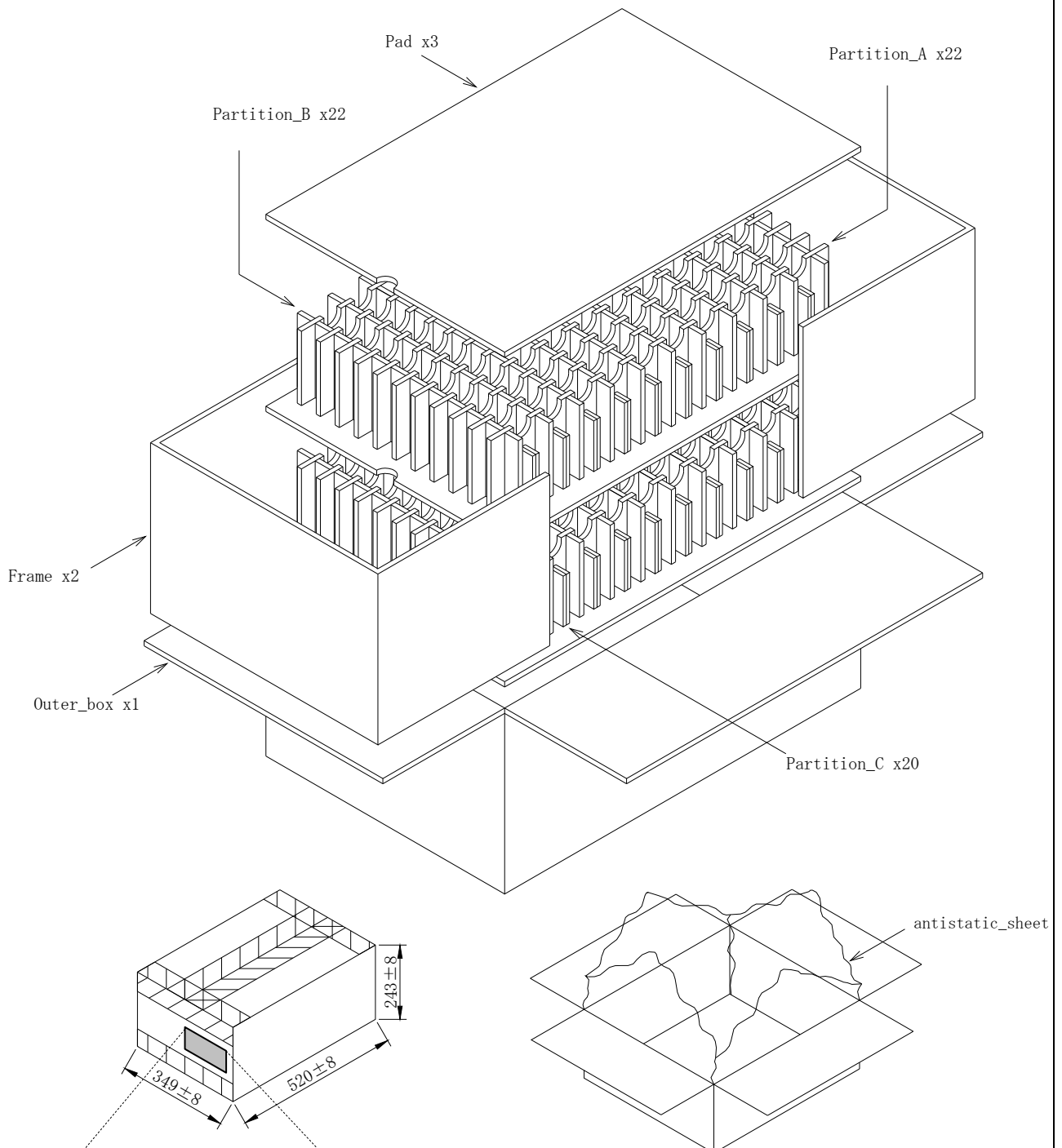
[15] MOUNTING DETALIS

Unit : mm



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[16] PACKAGEING DETAILS



TYPE	BS2F7HZ0169
	A3BS2F7HZ0169W
QUANTITY	200
LOT (DATE)	25 MAY 2008

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